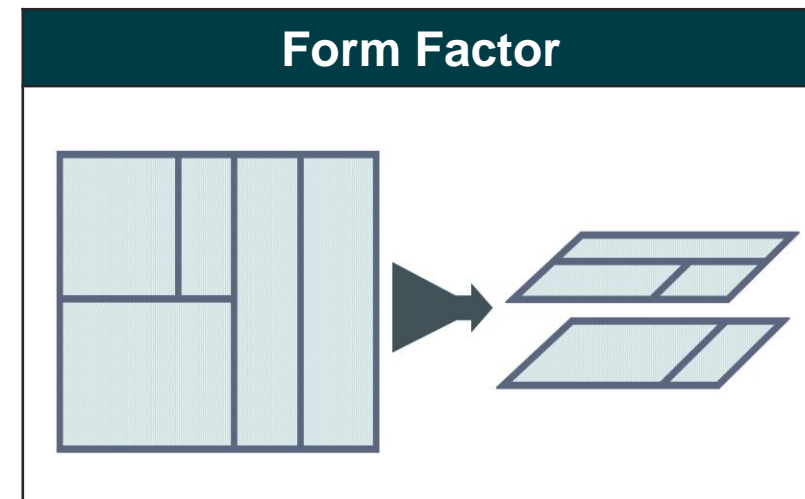
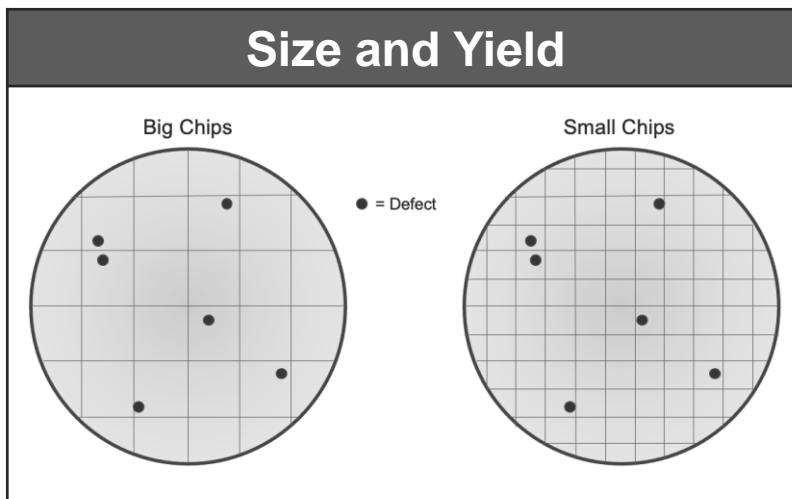
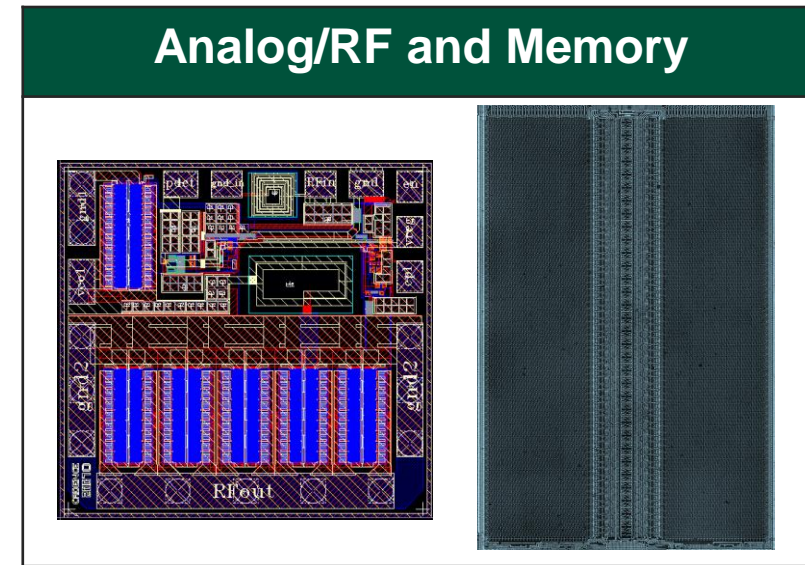
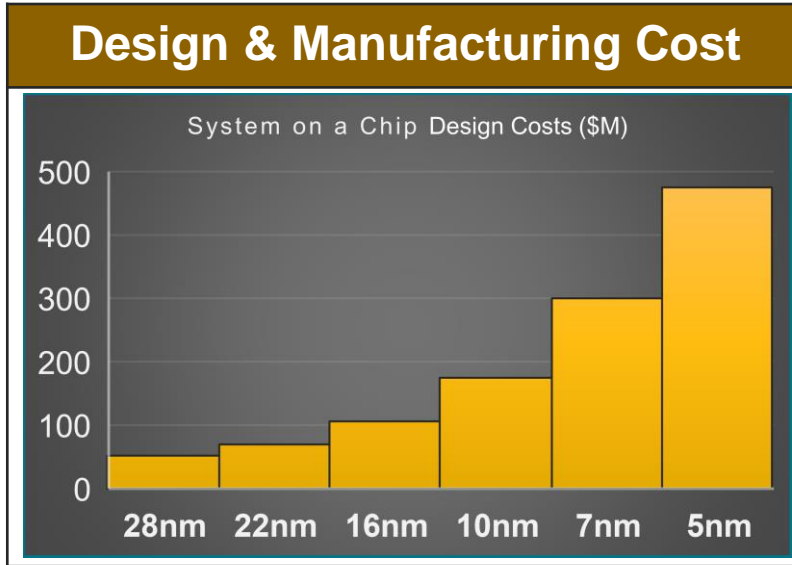




When Chips Become 3D Systems...The Challenges of 3DHI

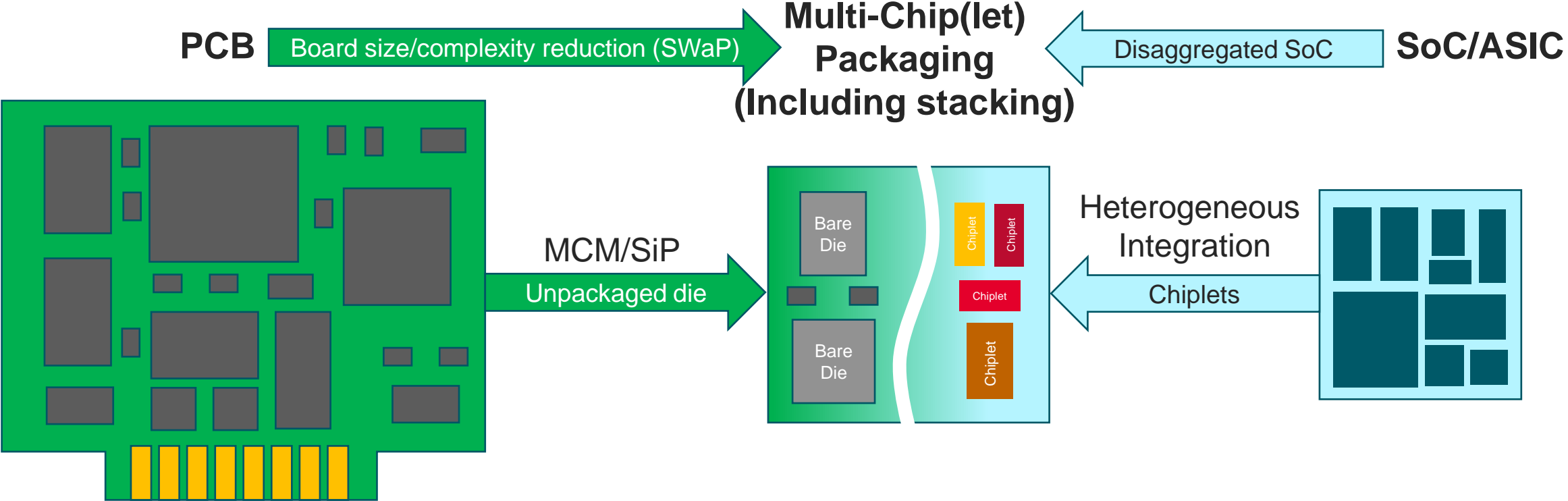
John Park (jpark@cadence.com)
Product Management Group Director

Simply Following Moore's Law Alone is No Longer the Best Technical and Economical Path Forward



SiP/MCM vs. Chiplet-Based (Heterogeneous Integration) Architectures

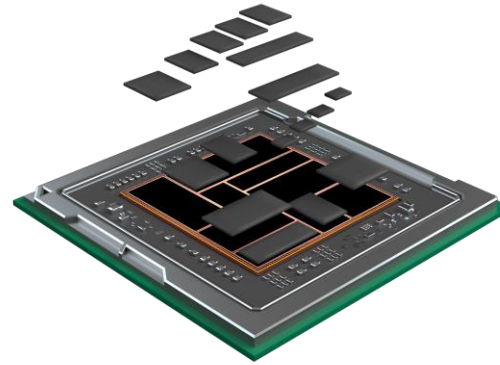
The transition from system on a chip (SoC) to system in a package (SiP)



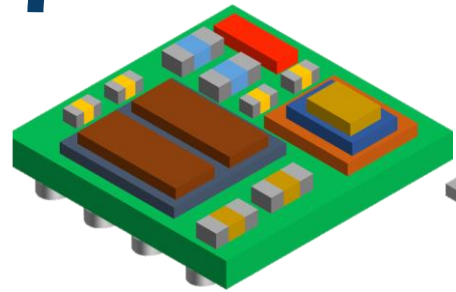
PCB to MCM/SiP Benefits
Smaller footprint
PCB simplification
Higher bandwidth
Lower power

SoC to HI Benefits
Reduced NRE costs
Shorter time to market
Larger than reticle size designs
More flexible IP use-model

Heterogeneous Integration Leverages Multiple Packaging Technologies

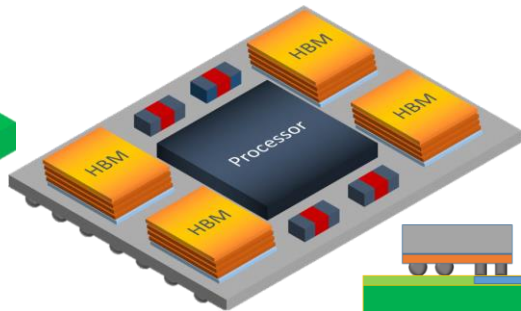


Heterogeneous Integration



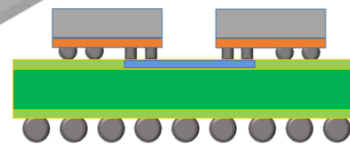
System in Package (SiP/MCM)

1990



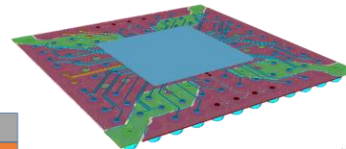
2.5D-IC (Silicon/RDL Interposer)

2010



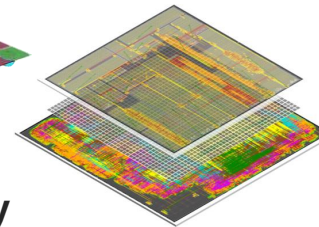
Interconnect Bridges

2012



Ultra-High-Density RDL (FOWLP)

2015



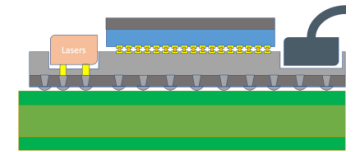
Silicon Stacking

2018



3D System-on-a-Wafer

2020

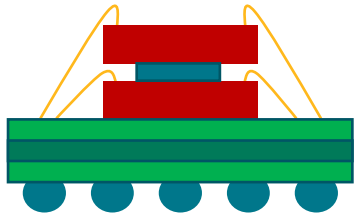


Co-Packaged Optics

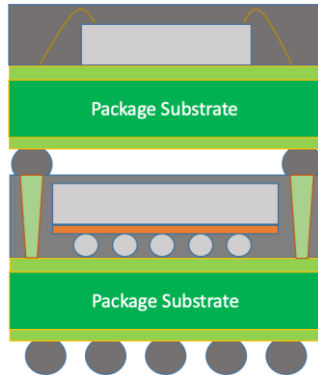
2022

The Nuances of 3DHI Packaging

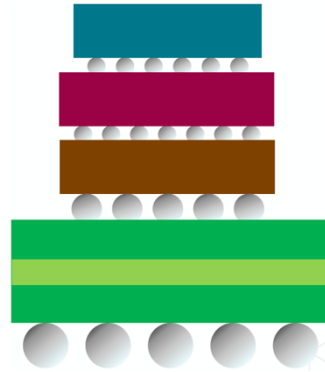
3D Packaging



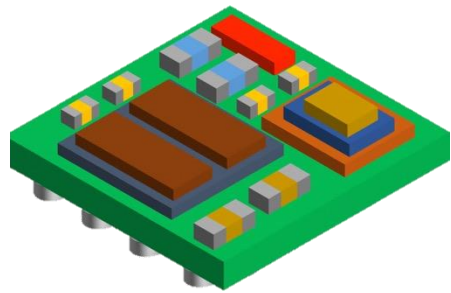
Wire-bonded BGA



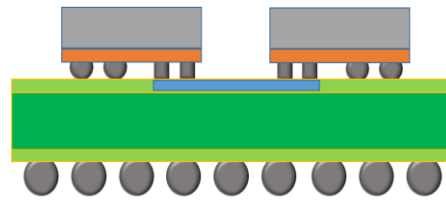
Package on package (PoP)



Micro-bump stacking

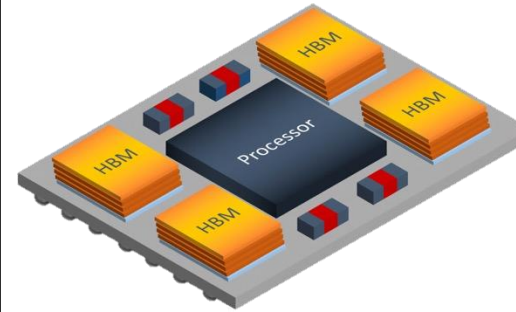


SiP/MCM

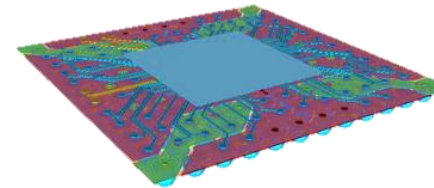


Interconnect bridges

Hybrid

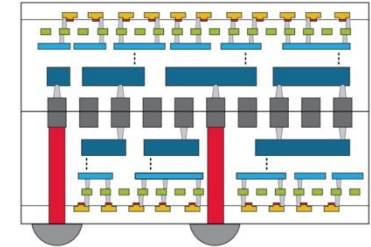


Silicon (TSV) interposer

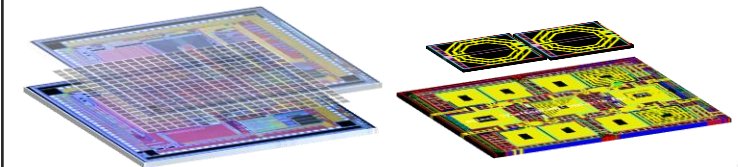


FOWLP
(Ultra-high-density RDL)

Silicon Stacking



Solder-bump-free stacking
Cu-to-Cu bonding, Direct bonding
Hybrid bonding

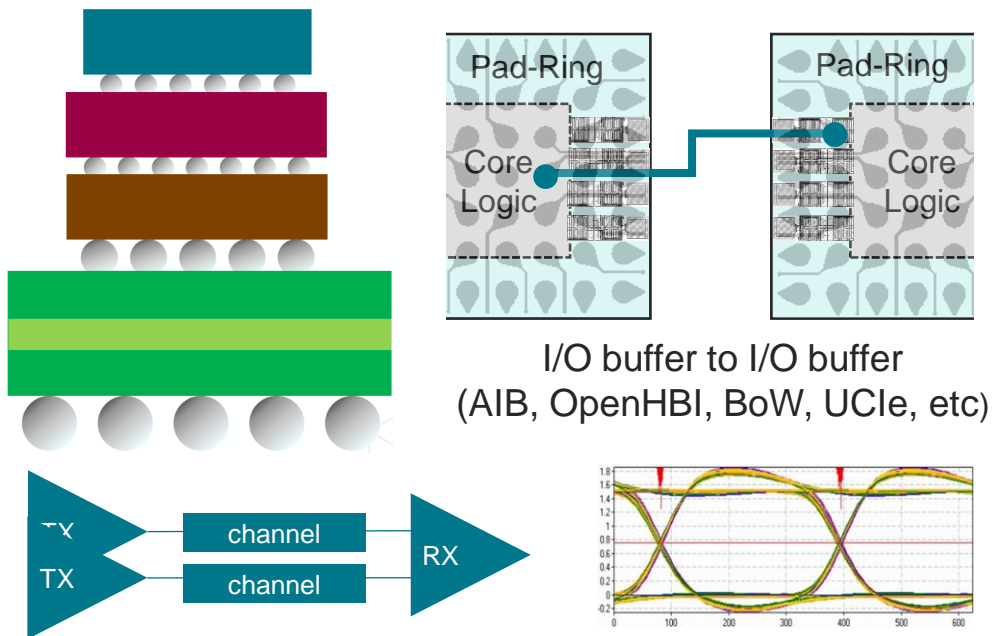


Core Macro and circuit stacking

3D Packaging Versus Silicon Stacking (3DHI)

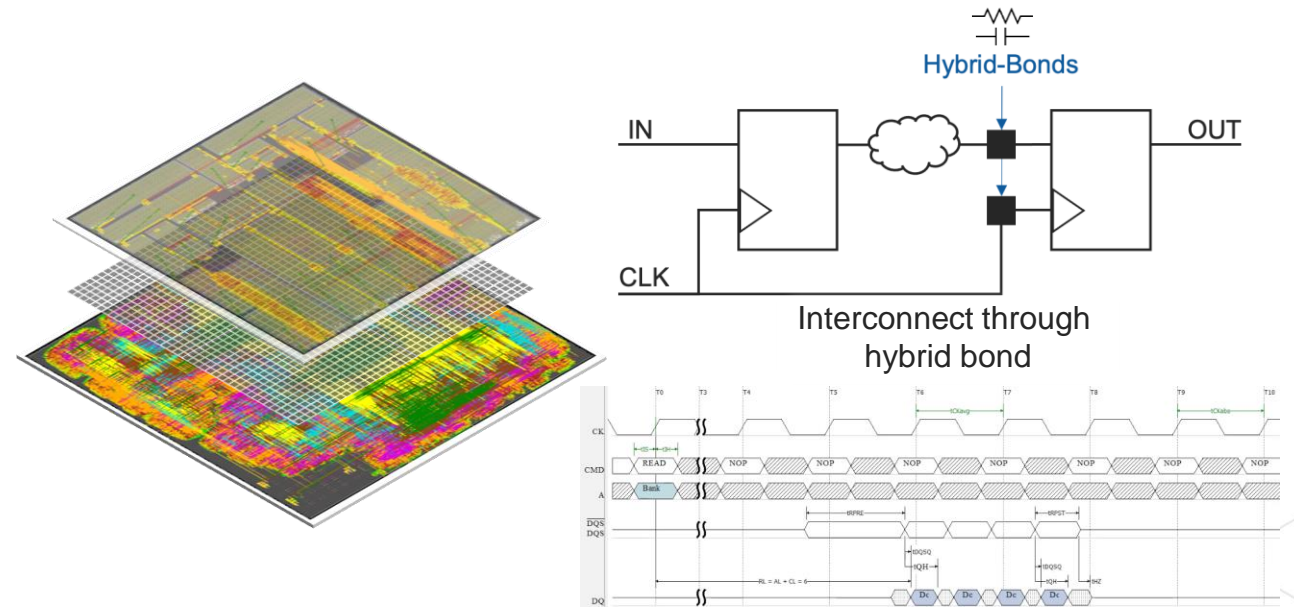
3D Packaging

- Solder-based connections
- Each die designed independently
- I/O buffer to I/O buffer signaling



Silicon Stacking

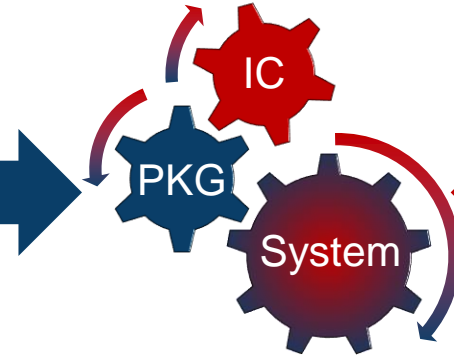
- Solder-free connections
- Single RTL partitioned at implementation
- DBI, hybrid-bond, cu-to-cu, direct connection



The Needs of IC and Systems Designers are Converging

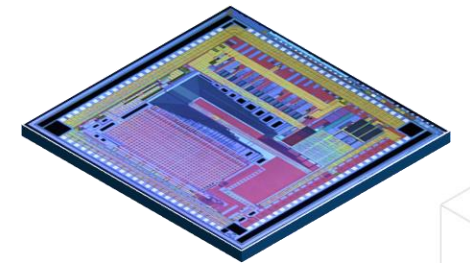
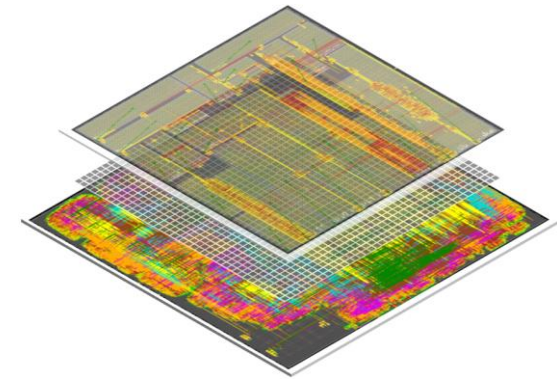
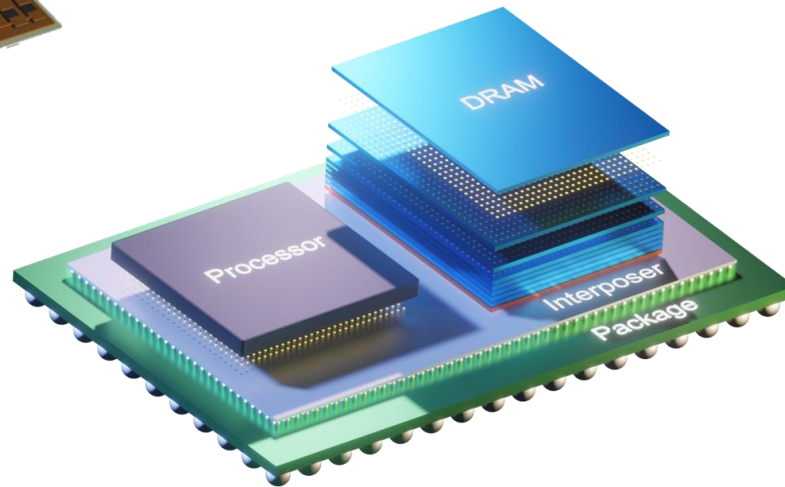
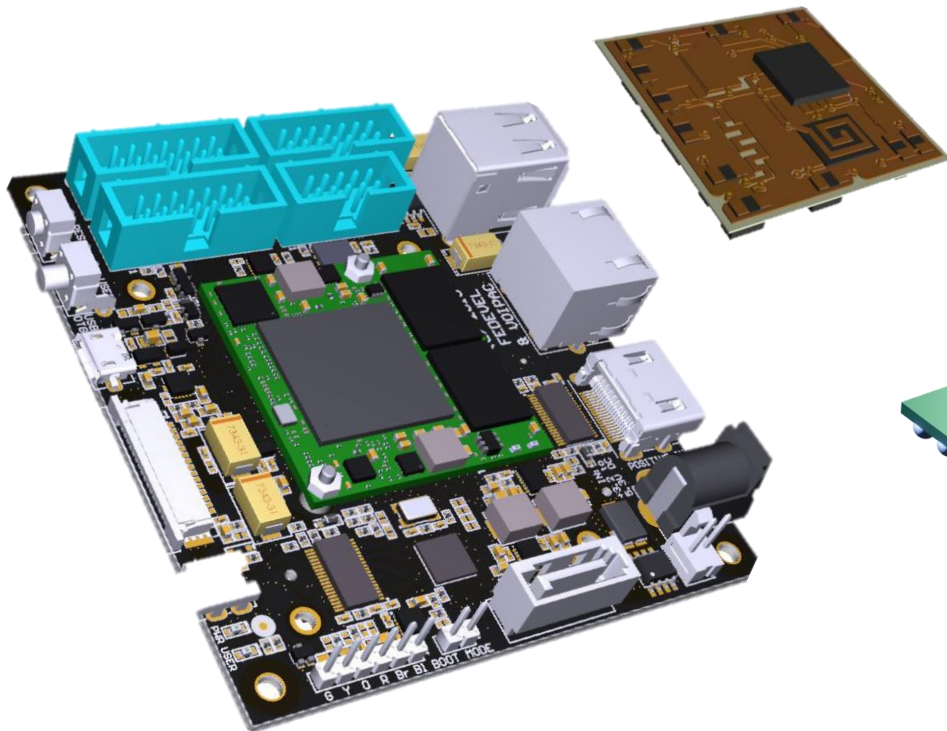
OSATs (SWaP)

1980-2010

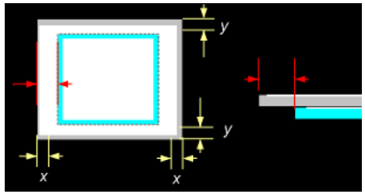


Foundries (PPA)

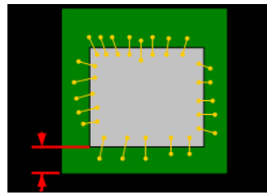
2011-Now



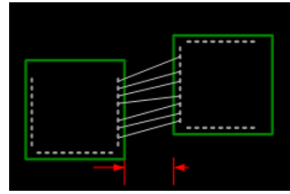
Multi-Chiplet 3D Ecosystem Challenges



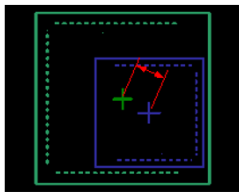
Die/Chiplet Overhang



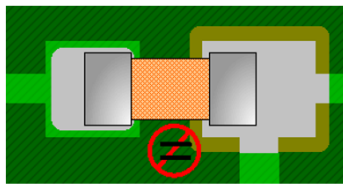
Die/Chiplet Spacing to Substrate Edge



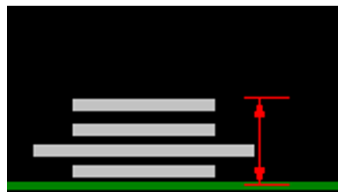
Die/Chiplet to Die/Chiplet Spacing



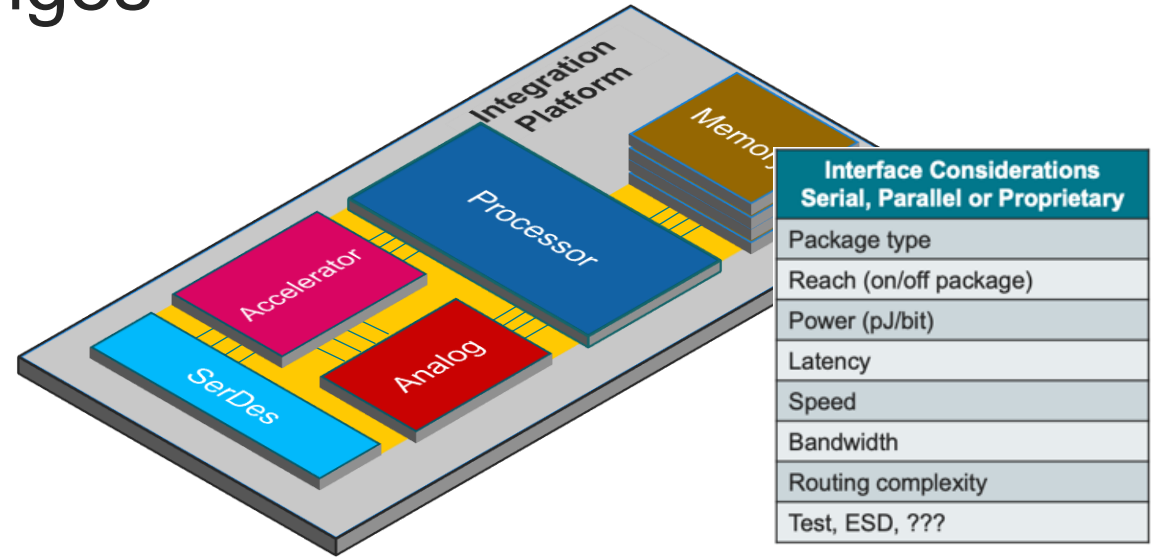
Die/Chiplet Center to Center Offset



Tombstone Effect (% size diff)



Die/Chiplet Stack Height



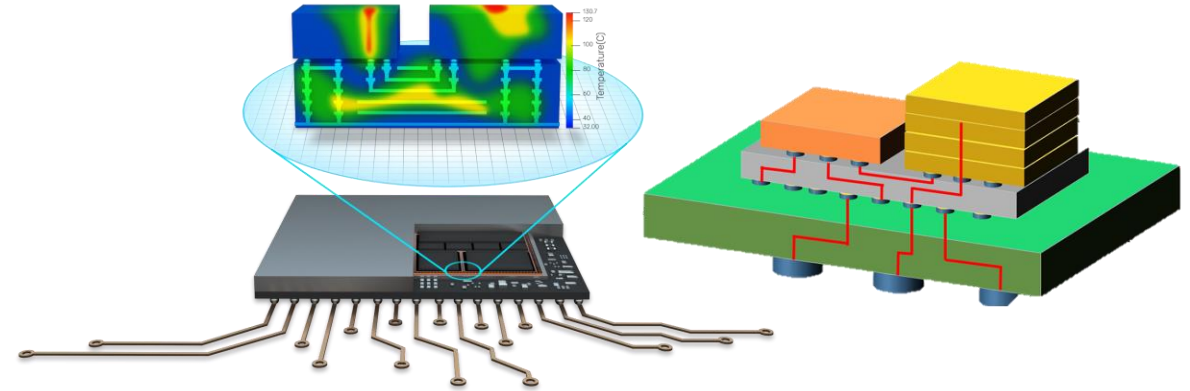
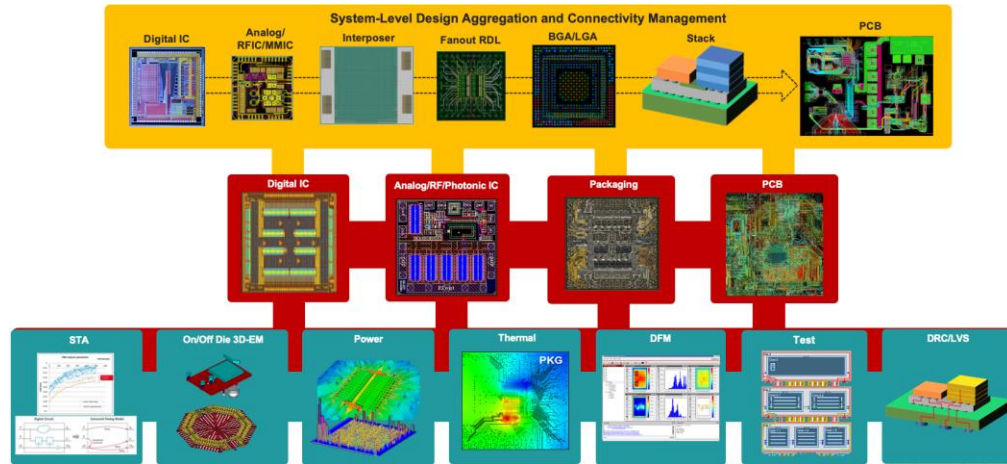
Assembly Design Kits

- PDK equivalent for the entire multi-chiplet assembly
- Historically, OSATs have not provided sufficient data to package designers
 - OSATs have large design centers to off-set this limited formal sharing of design requirements
- Foundries are helping to drive the concept of a PDK into the packaging world

COTS Chiplets

- Most chiplet-based designs are in a closed ecosystem
- Business case for IP companies to provide 3rd type of IP
- Standard exchange formats are lacking
- Common communication interface
 - AIB, UCIe, BoW, OpenHBI, ...
 - Too many packaging options to standardize on a single interface

Multi-Chiplet 3D Challenges



Complex Design Flows

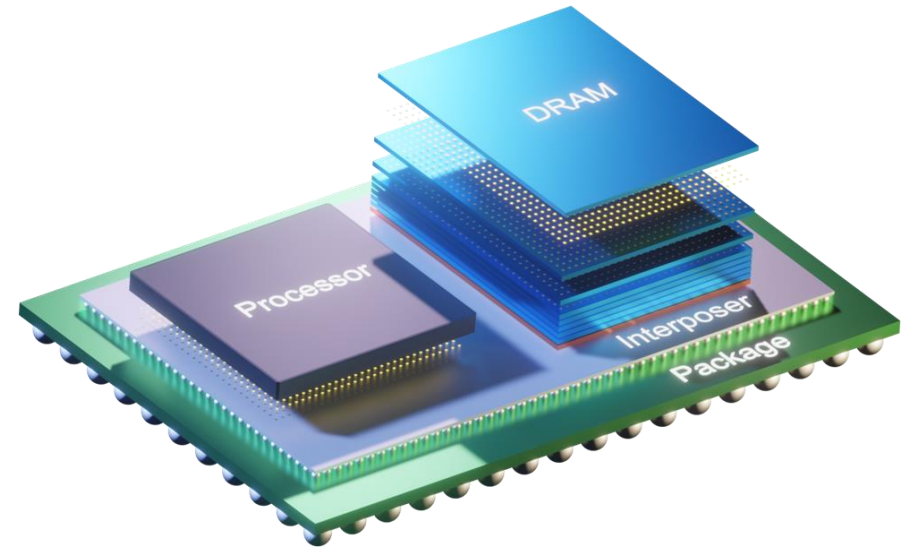
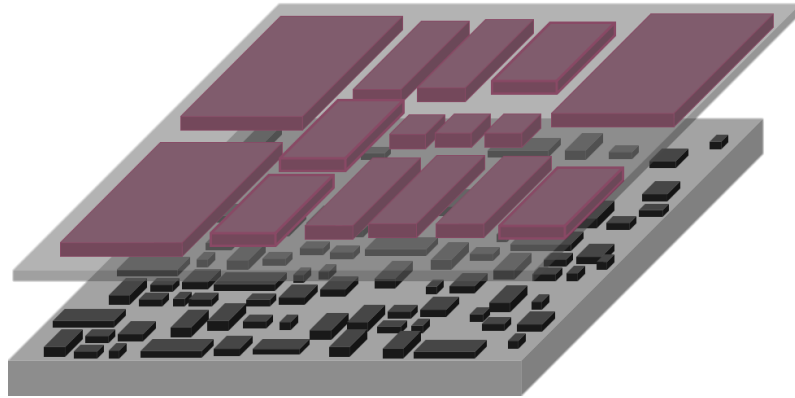
- Explosion in the number of design tools required
- System-level assembly planning, optimization and risk management
- Design partition strategies including D2D chiplets, thermal & off-package IO
- Need for common database for entire 3D-IC system
 - Chips, chiplets, tiles, packaging and PCB
 - Early-stage Thermal and Electrical analysis

Analysis and Sign-Off

- STA with automated corner reduction
- Rule-deck-free systemLVS
 - Alignment and connectivity checking
- Multi-die EMIR
 - Accounting for dynamic loading across multiple die
- Comprehensive thermal stress and CMP planarity checks
- New 3D-IC test standards
- Very large structures (billions of instances) need 3D-EM modeling



Multi-Chiplet 3D Challenges



3D Implementation

- Design size capacity
- Support for chiplets across multiple nodes/technologies (PDKs)
- Concurrent editing of multiple devices at full transistor-level detail
 - No abstraction
- On-the-fly die splitting and re-partitioning in Z direction
- Timing driven cross-chip(let) routing
- Co-design with packaging

Advanced Packaging

- Transitioning from laminate design to silicon design
 - Formal sign-off of DRC and LVS
- Differencing power/ground routing styles
 - Stripes/rails
 - Copper pour
- Advanced metal balancing
- Design capacity
 - Tens of thousands to hundreds of thousands (or more)

What to Look for in a Next-Generation 3D Integration Platform...

System-Level Aggregation, Optimization and Analysis

Top-Level Aggregation and Optimization

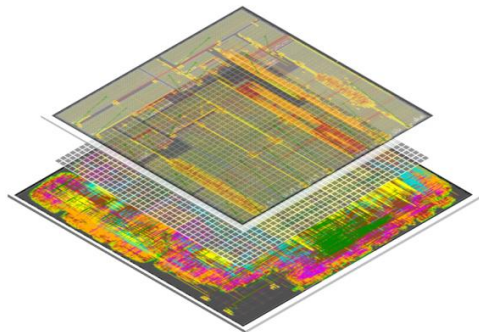
Early-Stage Thermal/Power Analysis

**Pre- & Post-Route Signal Integrity
Chiplet-to-Chiplet Electrical Compliance**

STA

Sign-Off DRC/LVS

Silicon Stacking



Silicon Stacking

Advanced Multi-Die/Chiplet Packaging

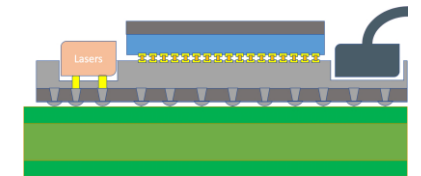
FOWLP

BGA/LGA

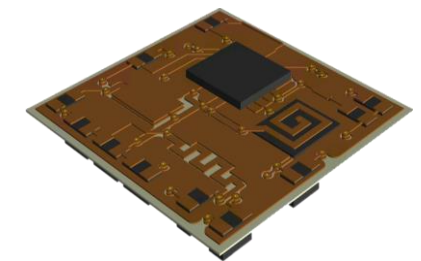
Si/RDL Interposer

Interconnect Bridge

RF/Photonics



Co-Packaged Optics



RF Module

Summary



Advanced Packaging and 3DHI are Driving More-Than-Moore

Heterogenous Integration Leverages Multiple Packaging Technologies

Several New Challenges Facing Designers Moving to 3DHI

Is it Time to Reevaluate Your Design Methodology?



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